

FIG. 1

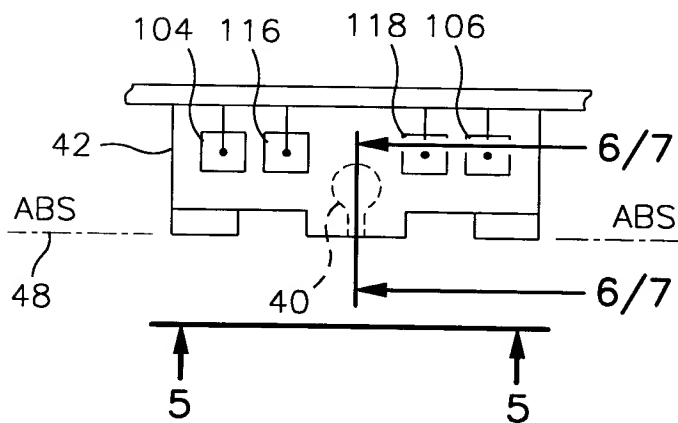


FIG. 2

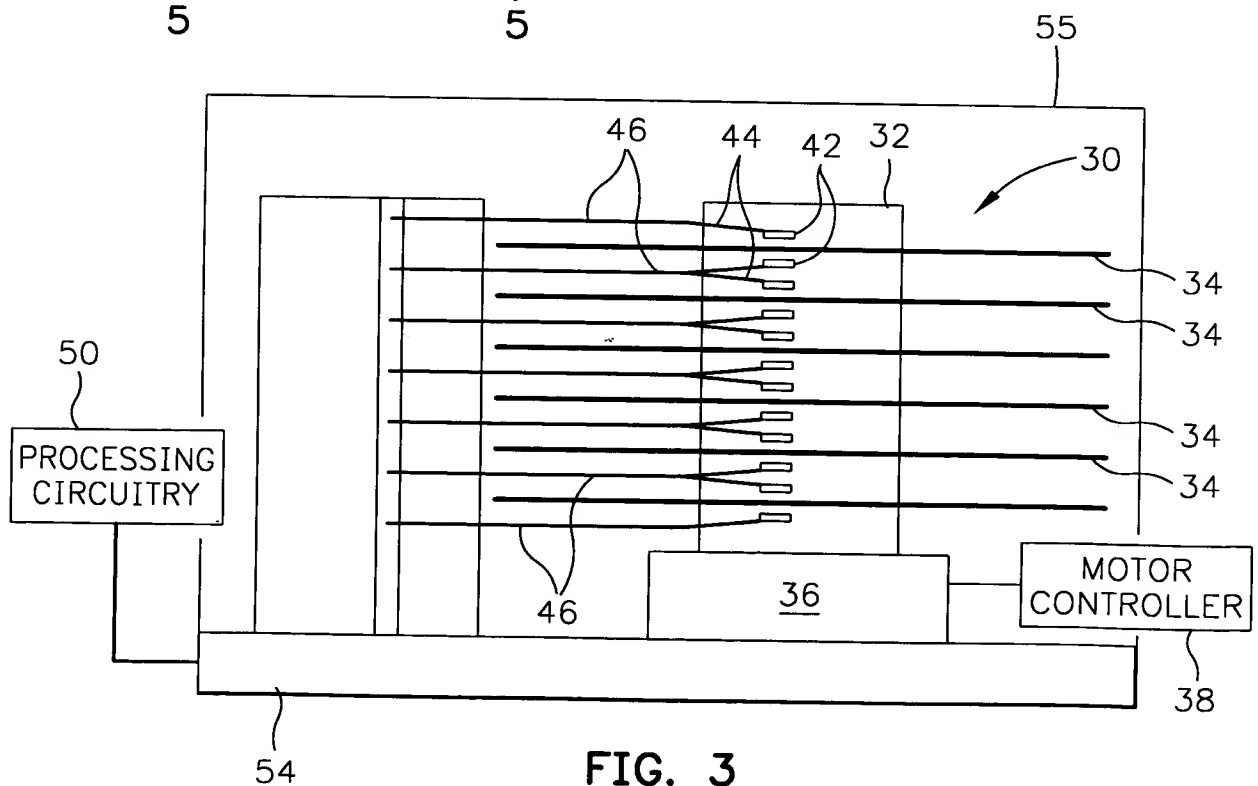


FIG. 3

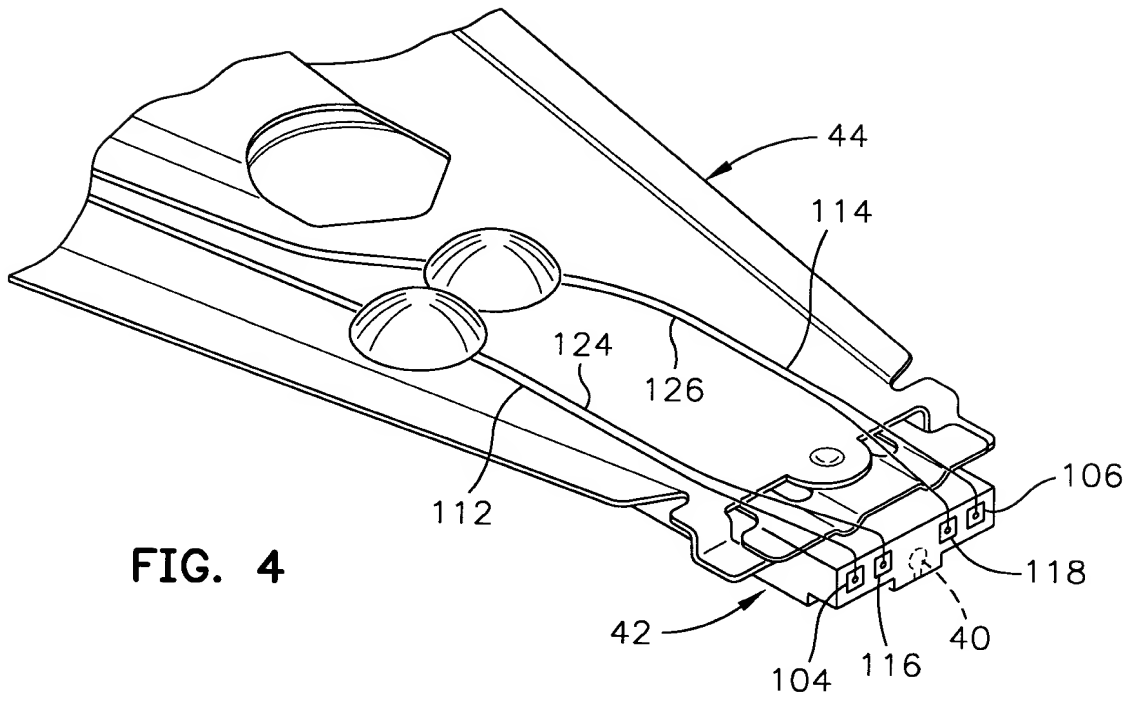


FIG. 4

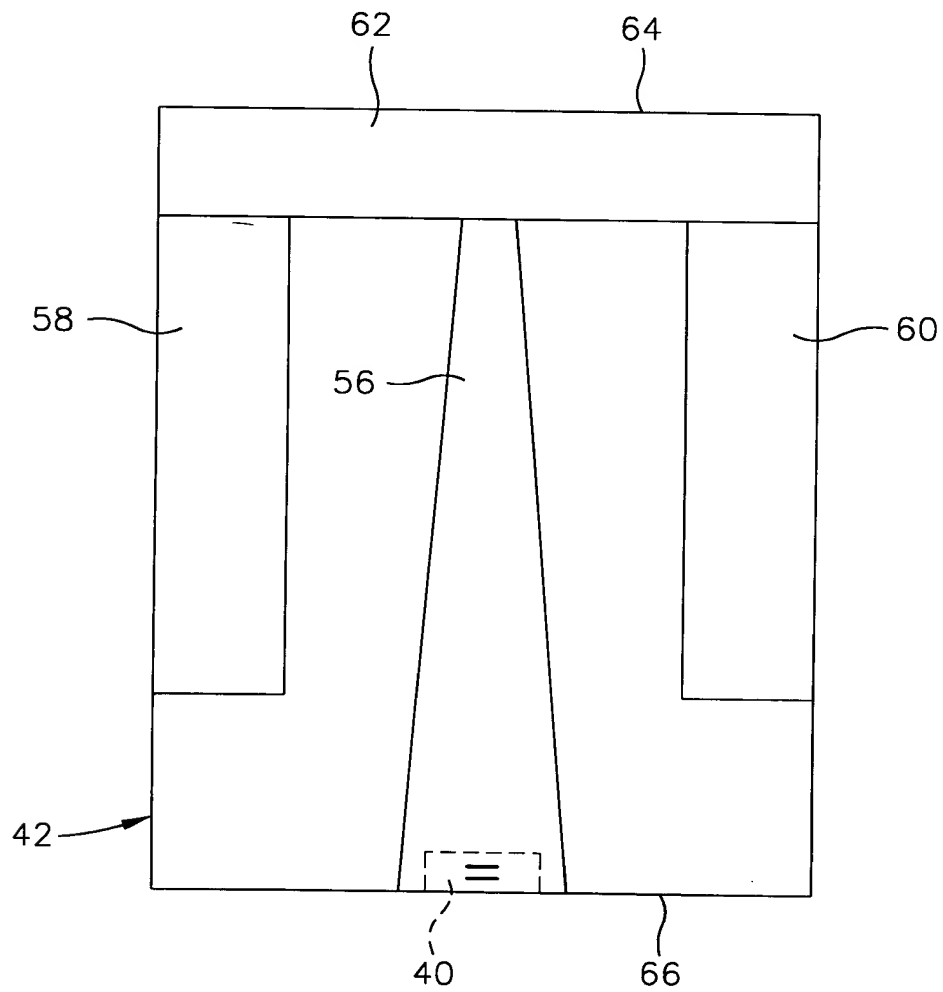


FIG. 5

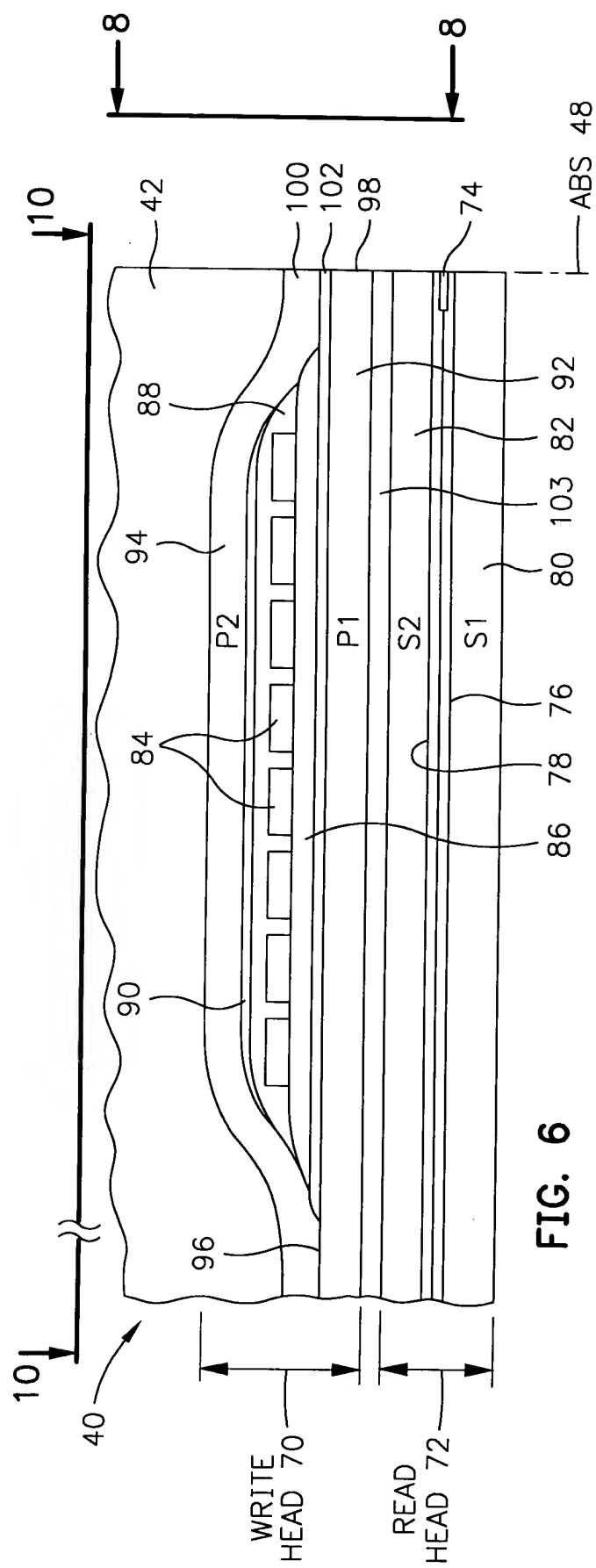


FIG. 6

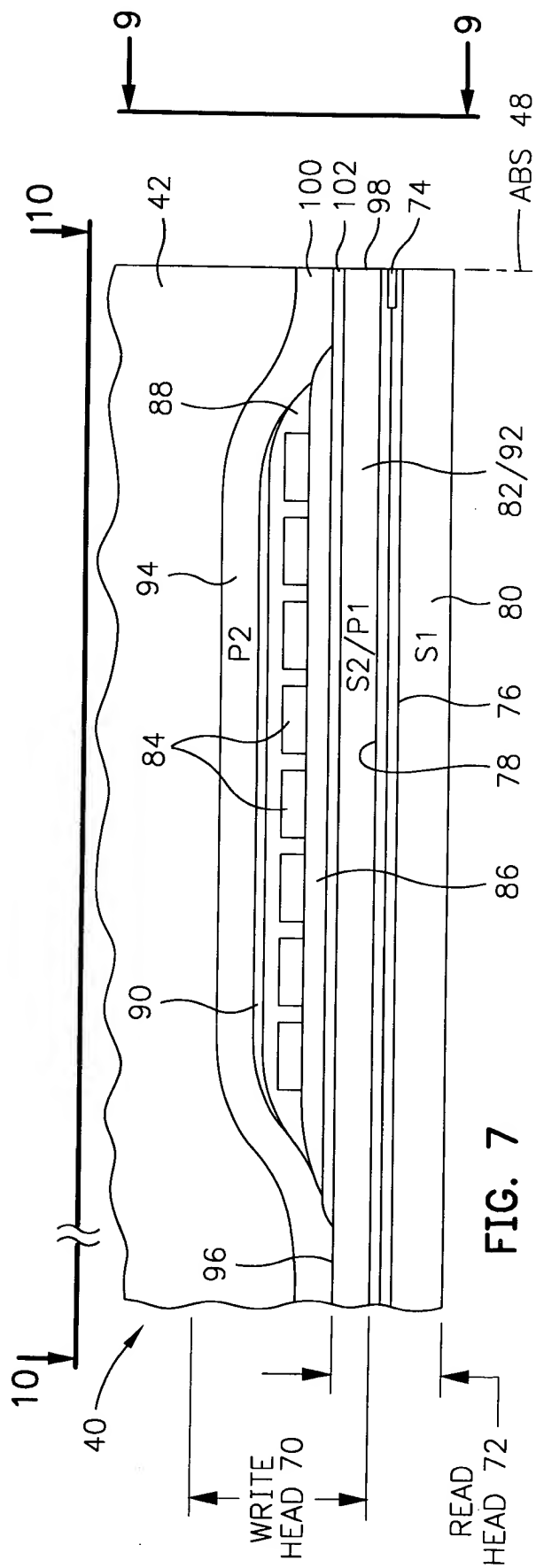


FIG. 7

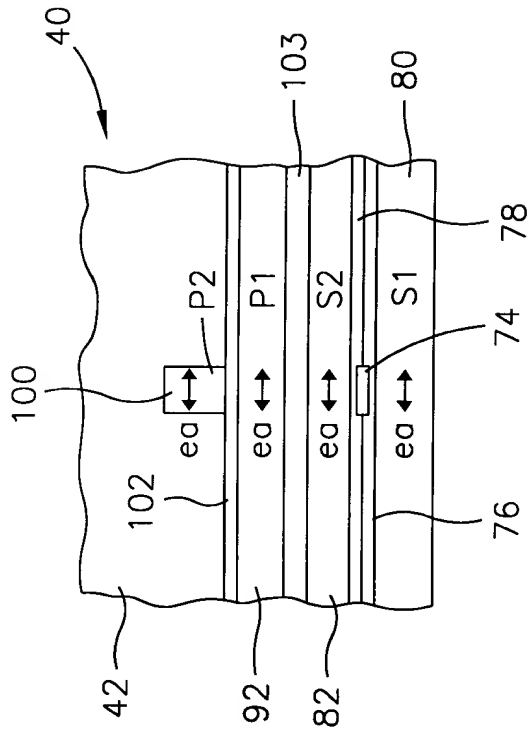


FIG. 8

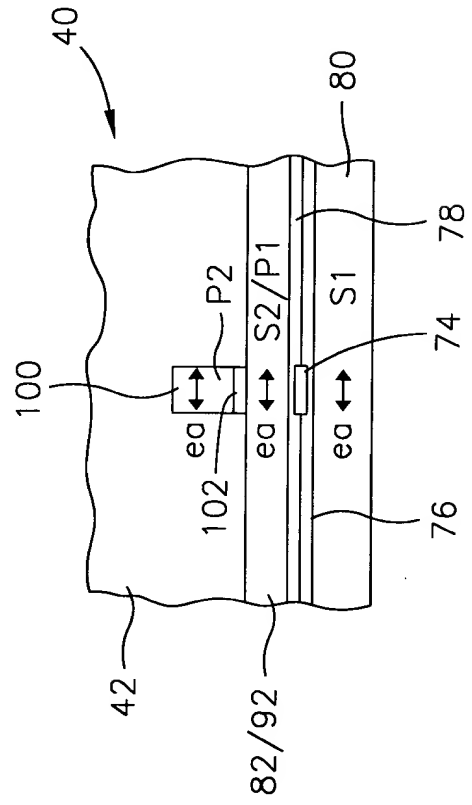


FIG. 9

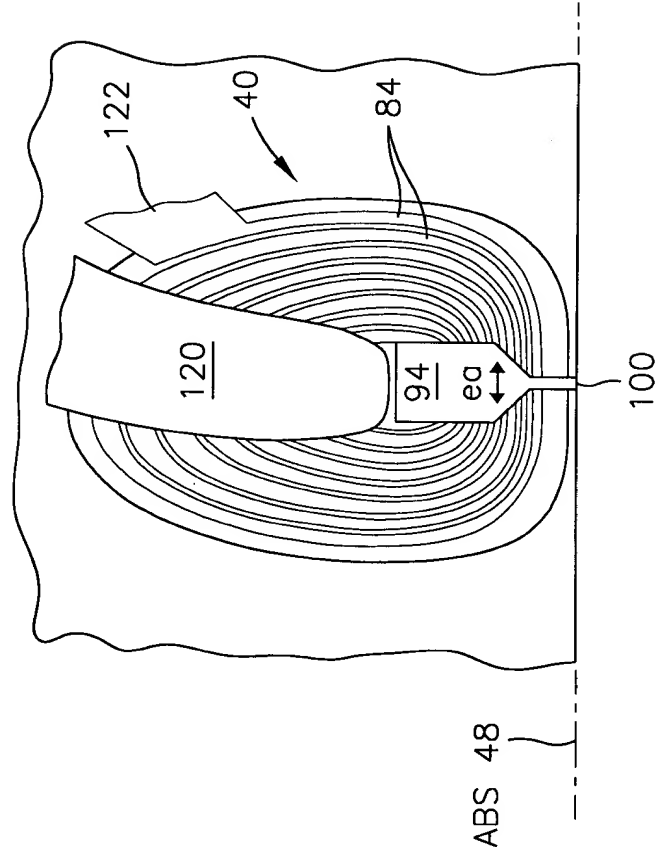


FIG. 10

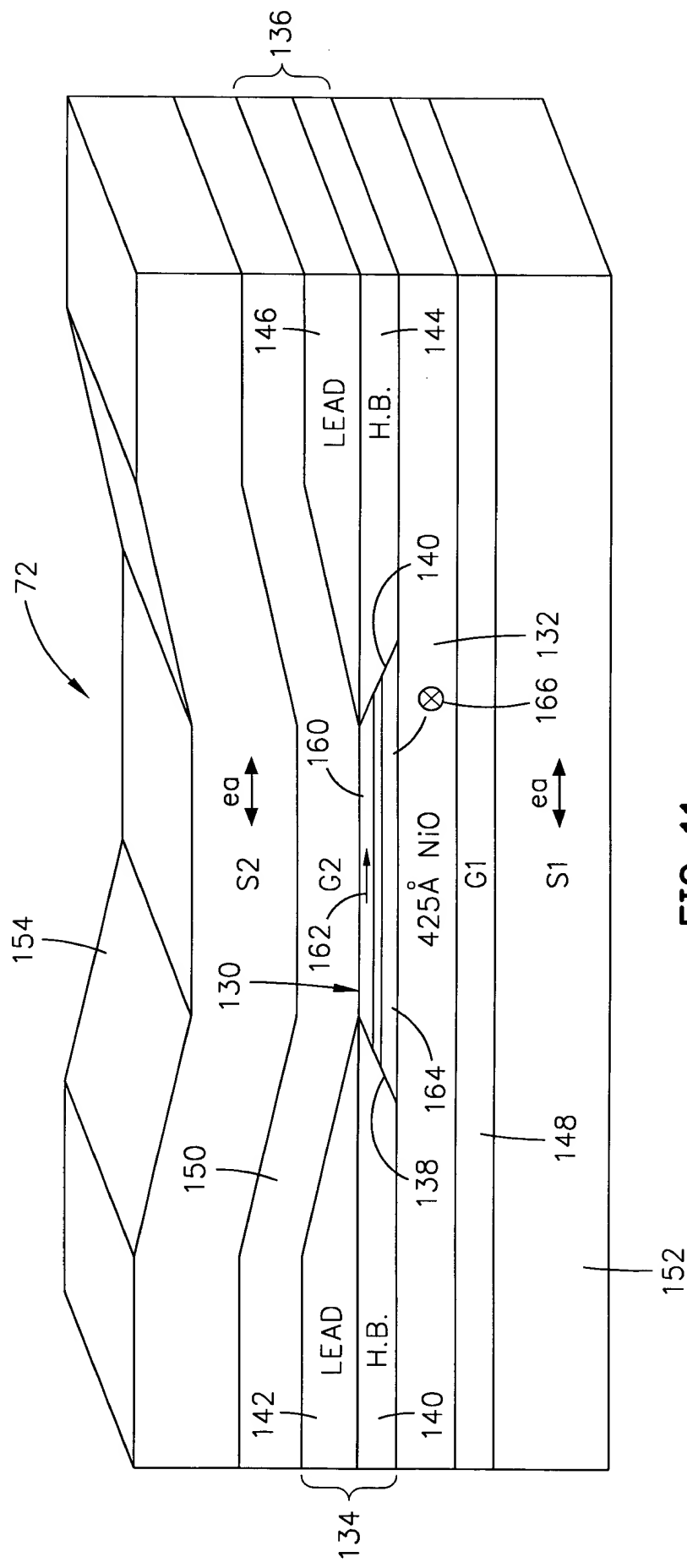


FIG. 11
(ABS)

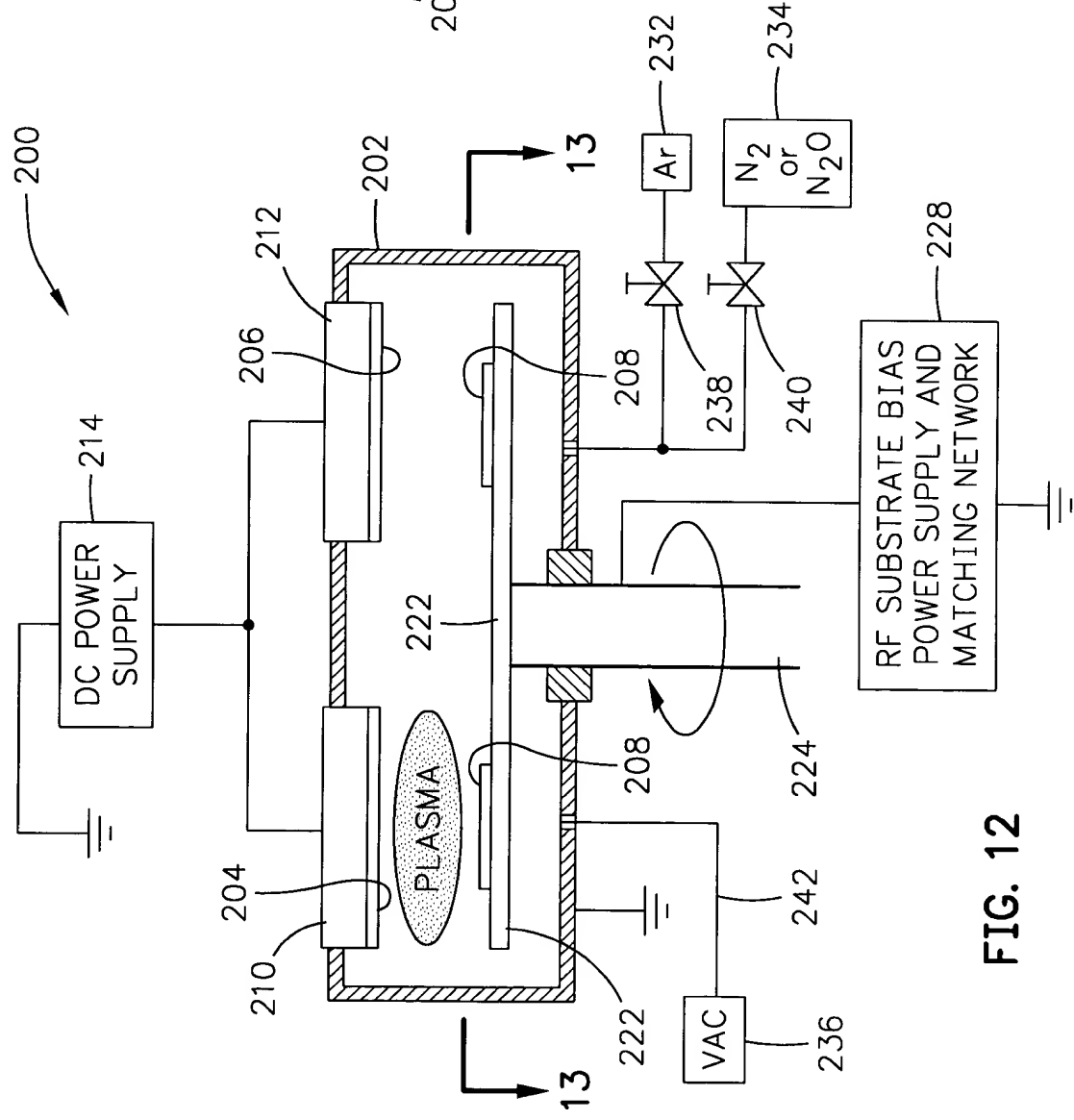


FIG. 12

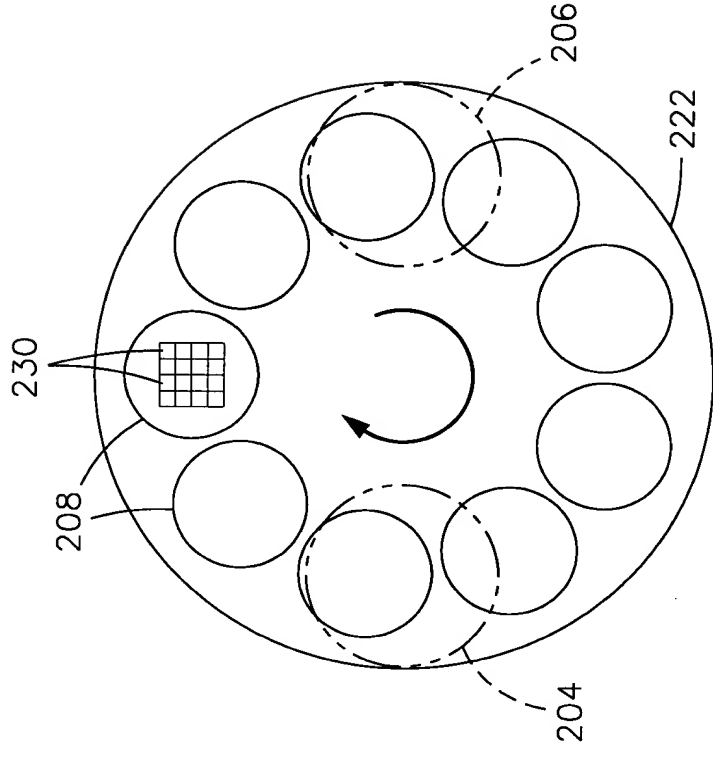


FIG. 13

FIG. 14

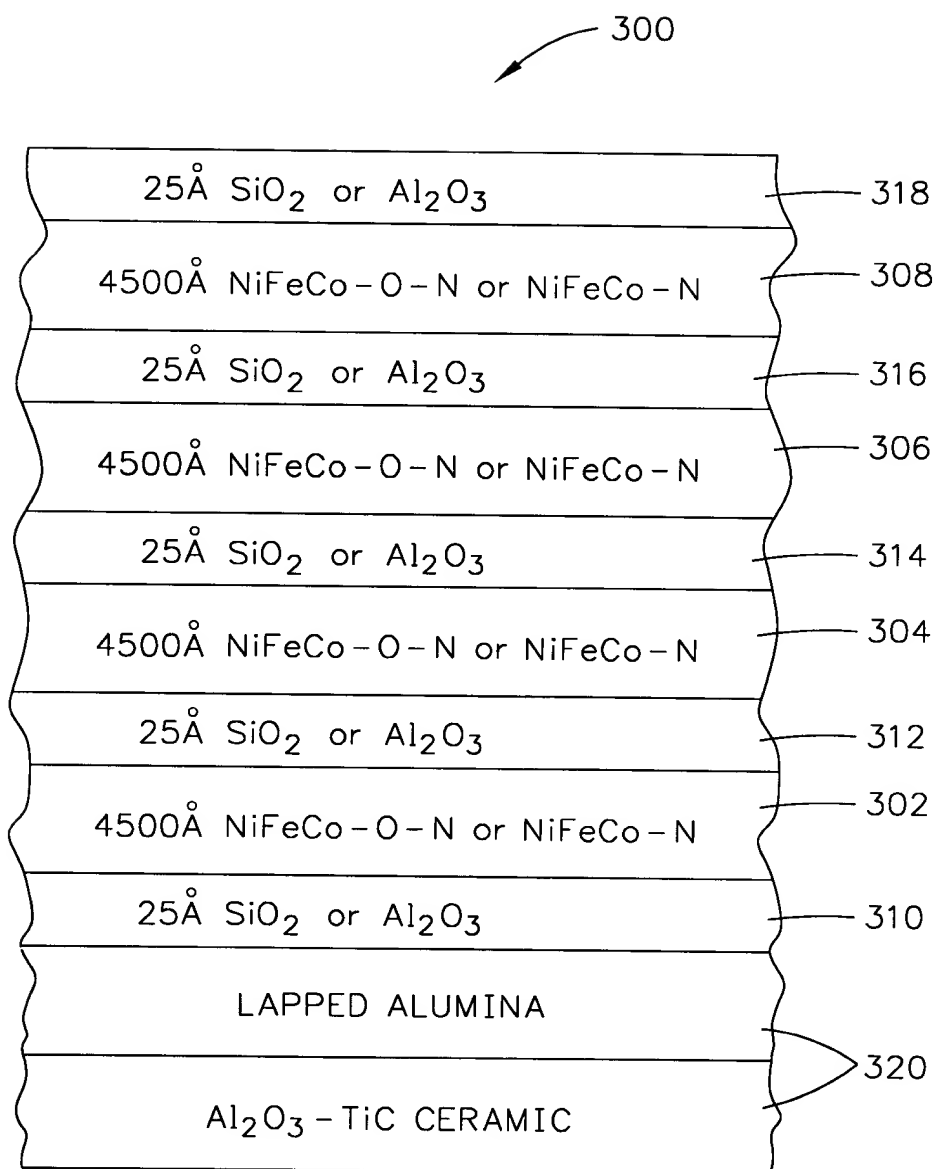
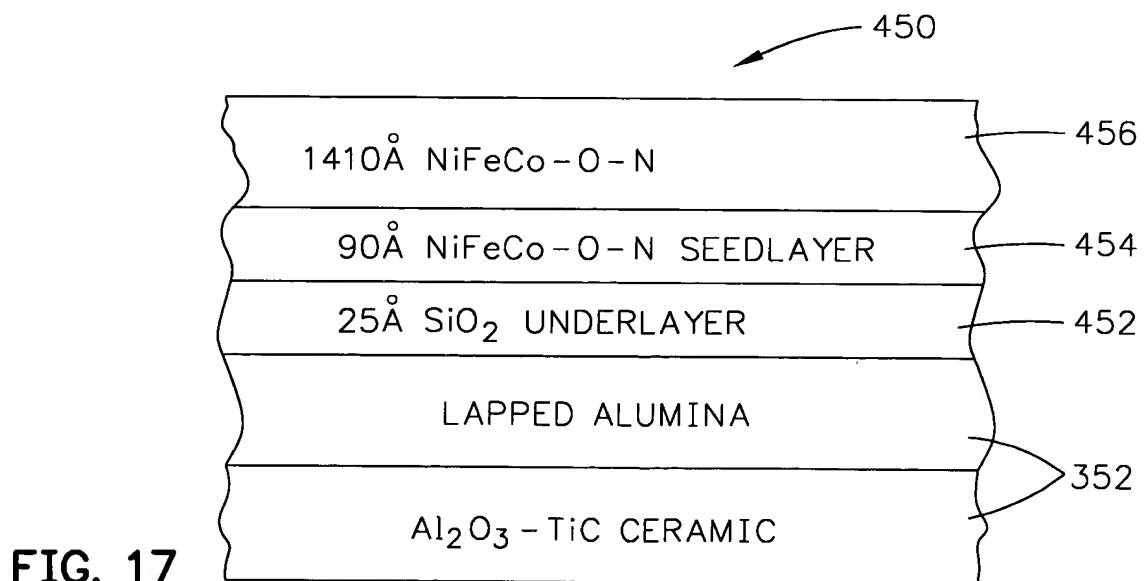
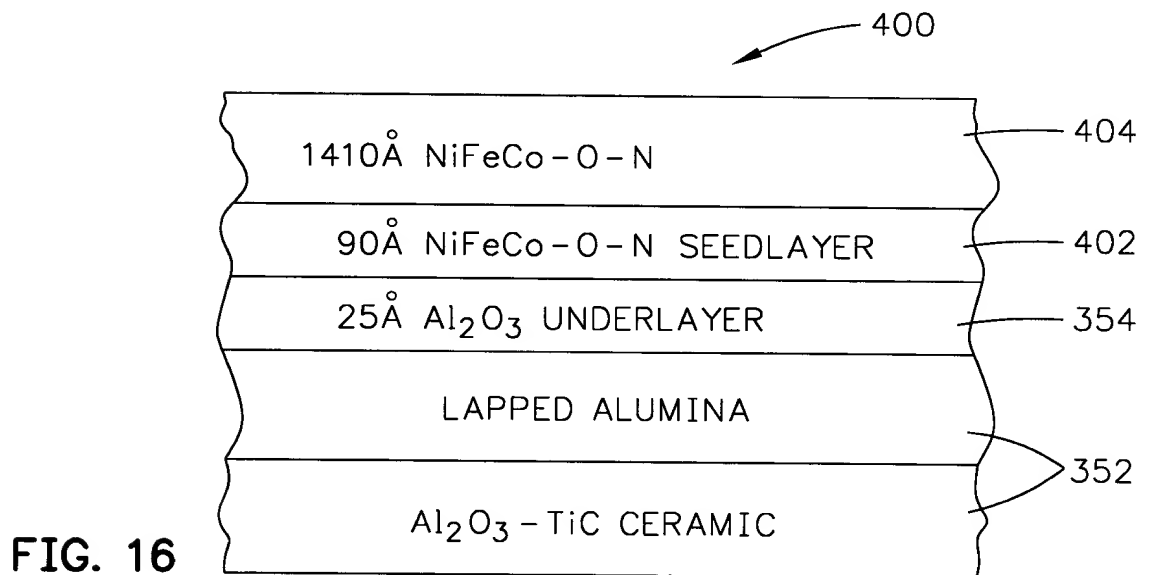
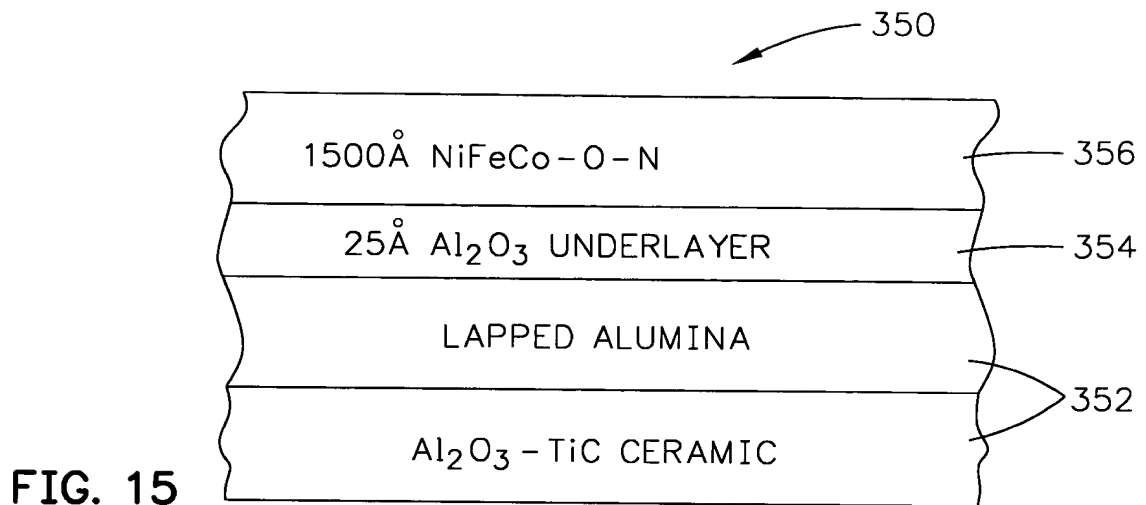


FIG. 14



THICKNESS AND N₂O CONCENTRATION
DEPENDENCE OF IN-PLANE AND VERTICAL H_k IN
SINGLE LAYER AND LAMINATED NiFeCo-O-N FILMS
(DC MAG 1750 W, 2.0X10⁻³ mbar, NO BIAS)

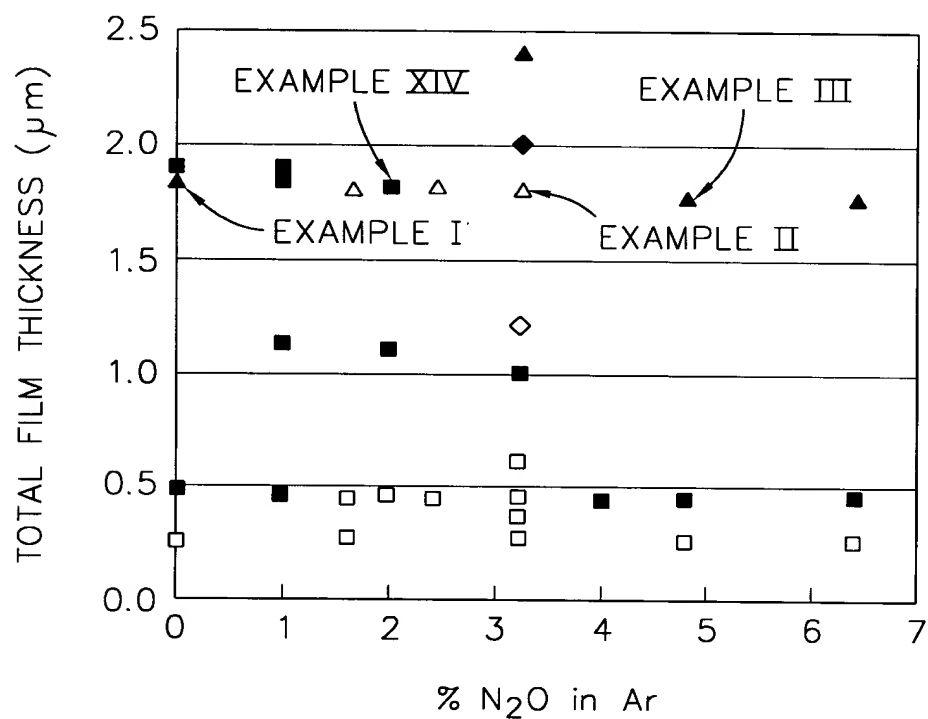
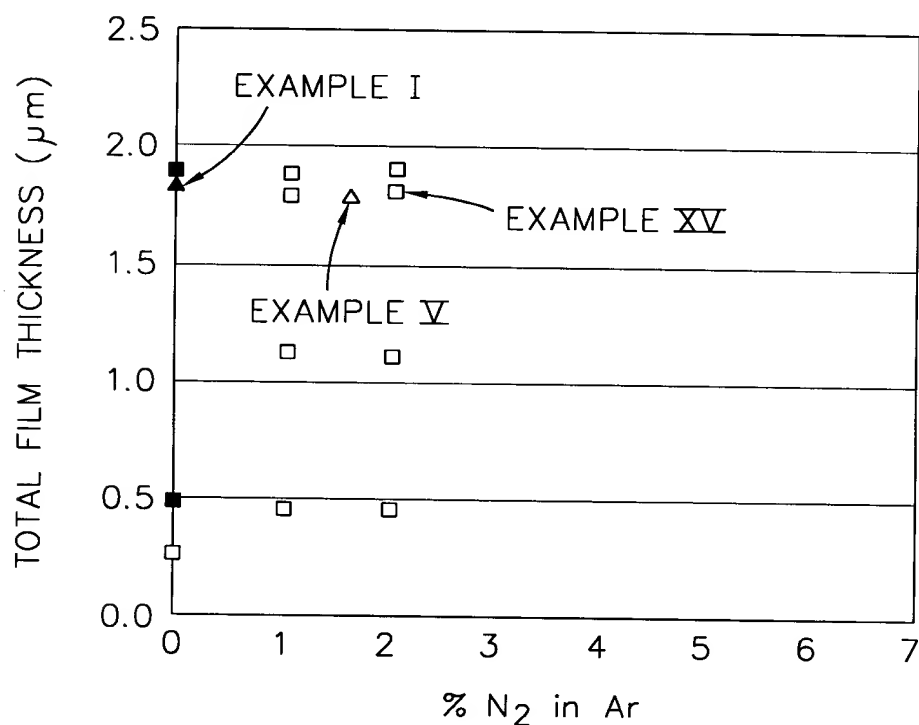


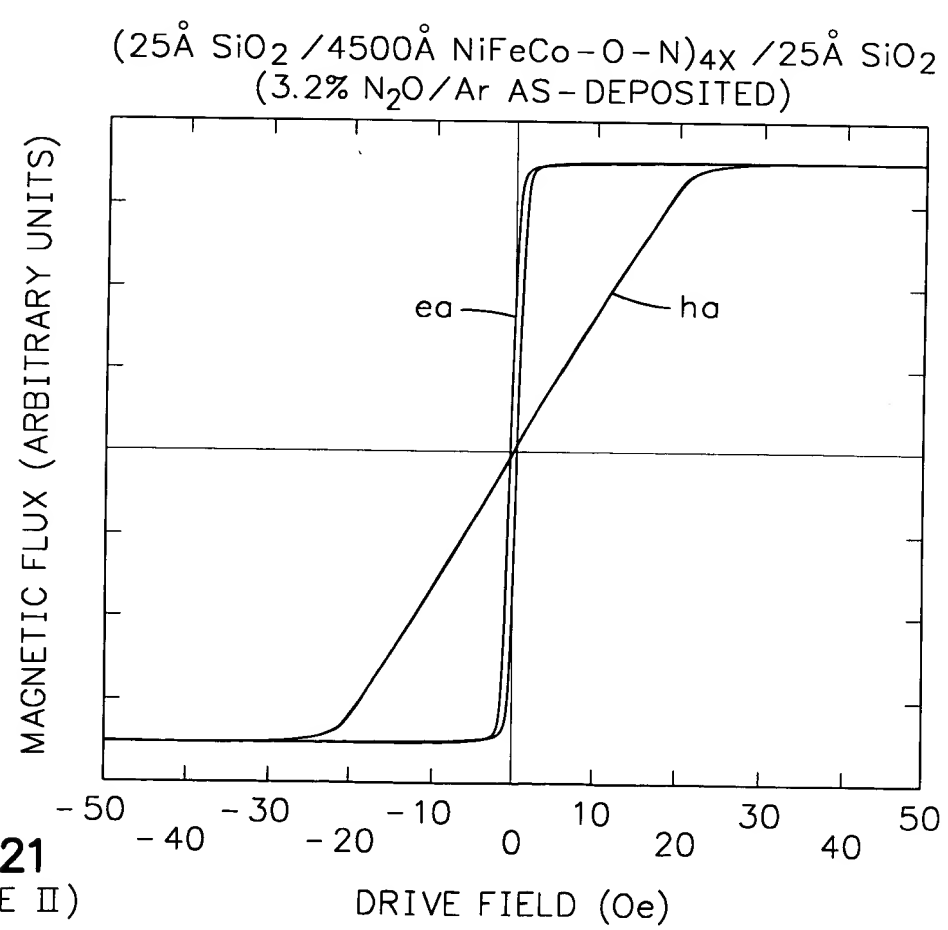
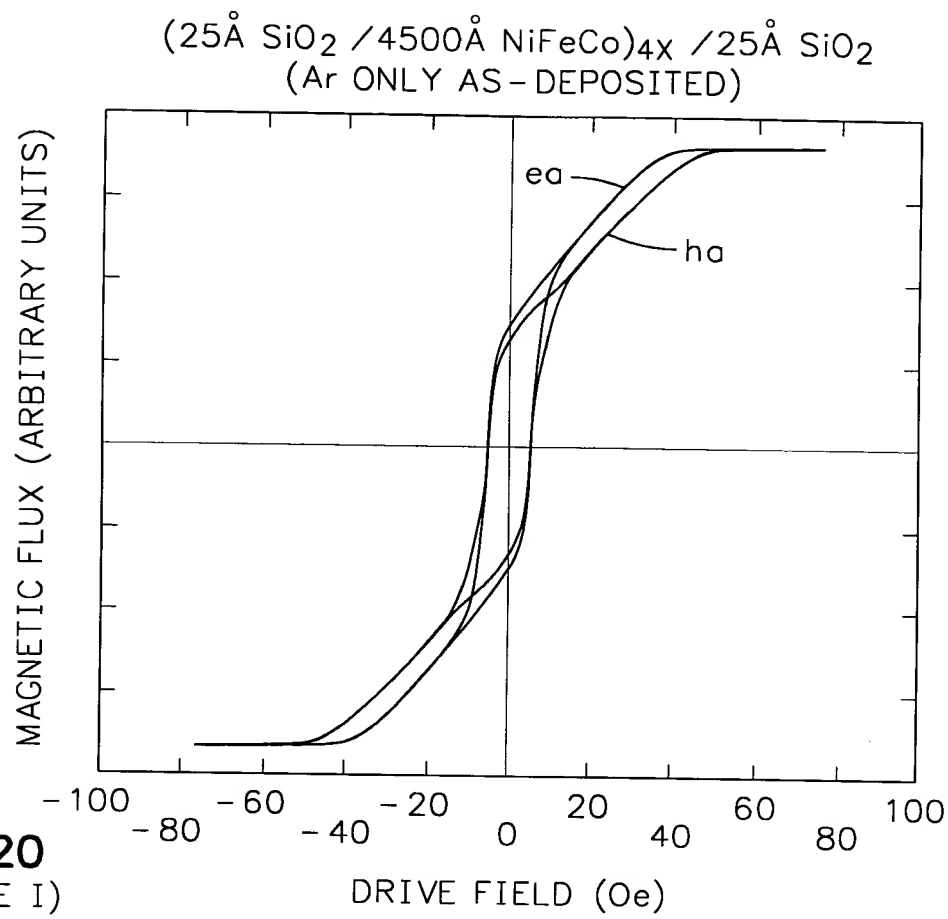
FIG. 18

THICKNESS AND N₂ CONCENTRATION
DEPENDENCE OF IN-PLANE AND VERTICAL H_k IN
SINGLE LAYER AND LAMINATED NiFeCo-N FILMS
(DC MAG 1750 W, 2.0X10⁻³ mbar, NO BIAS)



- SINGLE LAYER FILMS-IN PLANE H_k
- △ 4X LAMINATED FILMS-IN PLANE H_k
- SINGLE LAYER FILMS-VERTICAL H_k
- ▲ 4X LAMINATED FILMS-VERTICAL H_k

FIG. 19



(18Å ALUMINA/4500Å NiFeCo-N)₄X / 25Å ALUMINA
(1.6% N₂ /Ar AS-DEPOSITED)

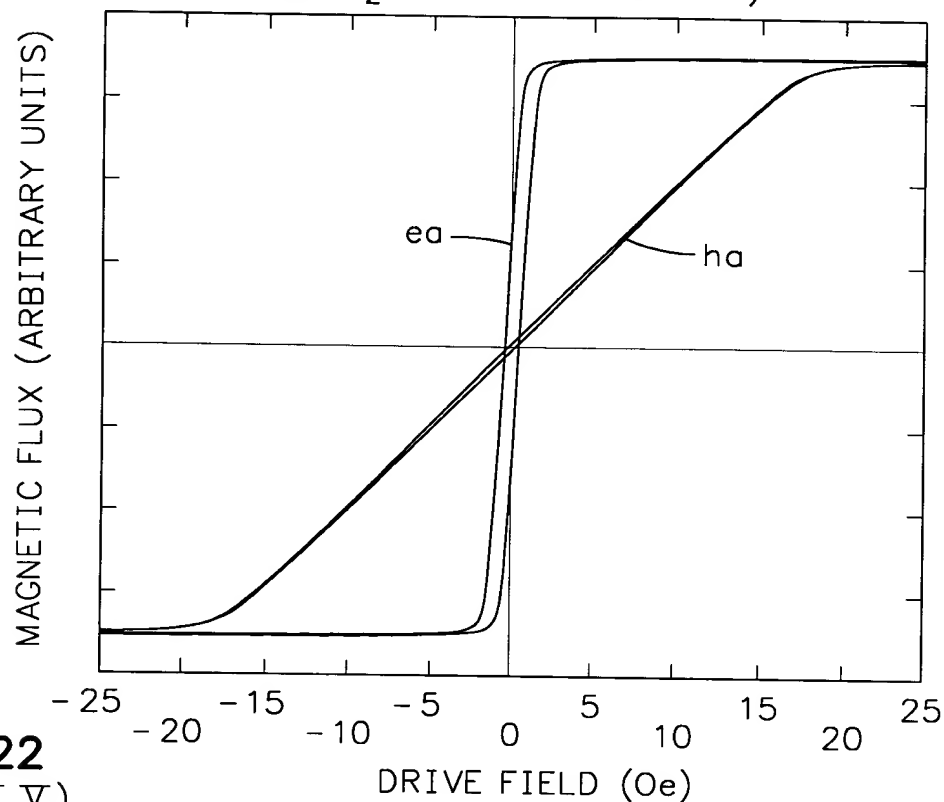


FIG. 22
(EXAMPLE V)

25Å ALUMINA/1.80μm NiFeCo-O-N/25Å ALUMINA
(2.0% N₂O/Ar AS-DEPOSITED)

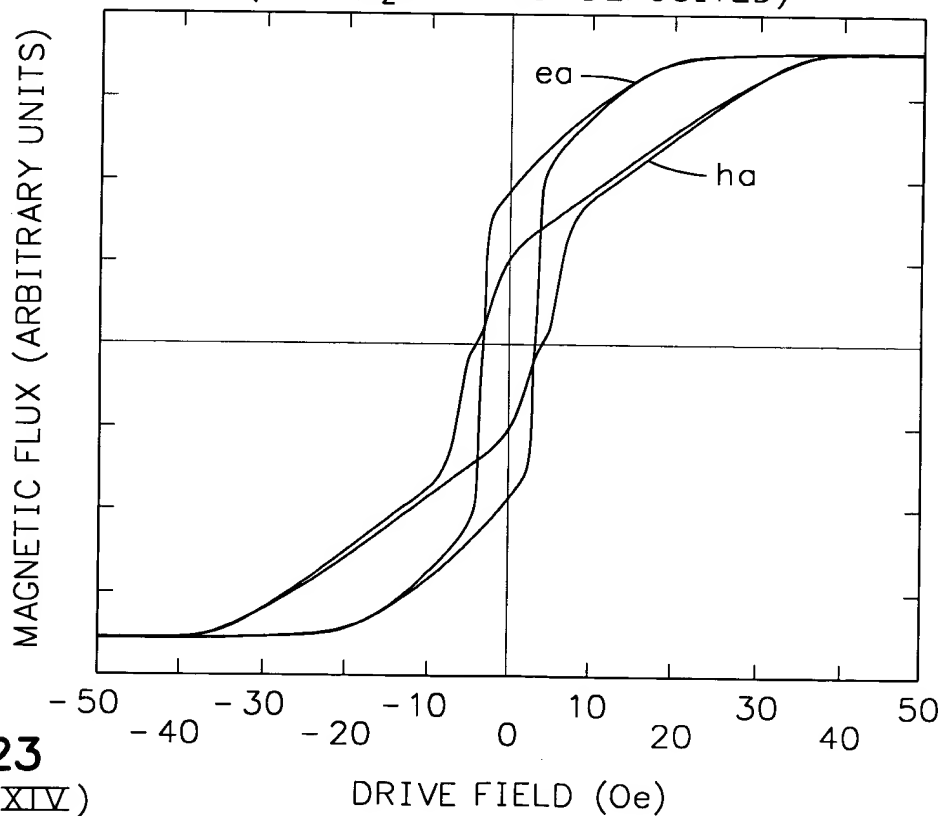


FIG. 23
(EXAMPLE XIV)

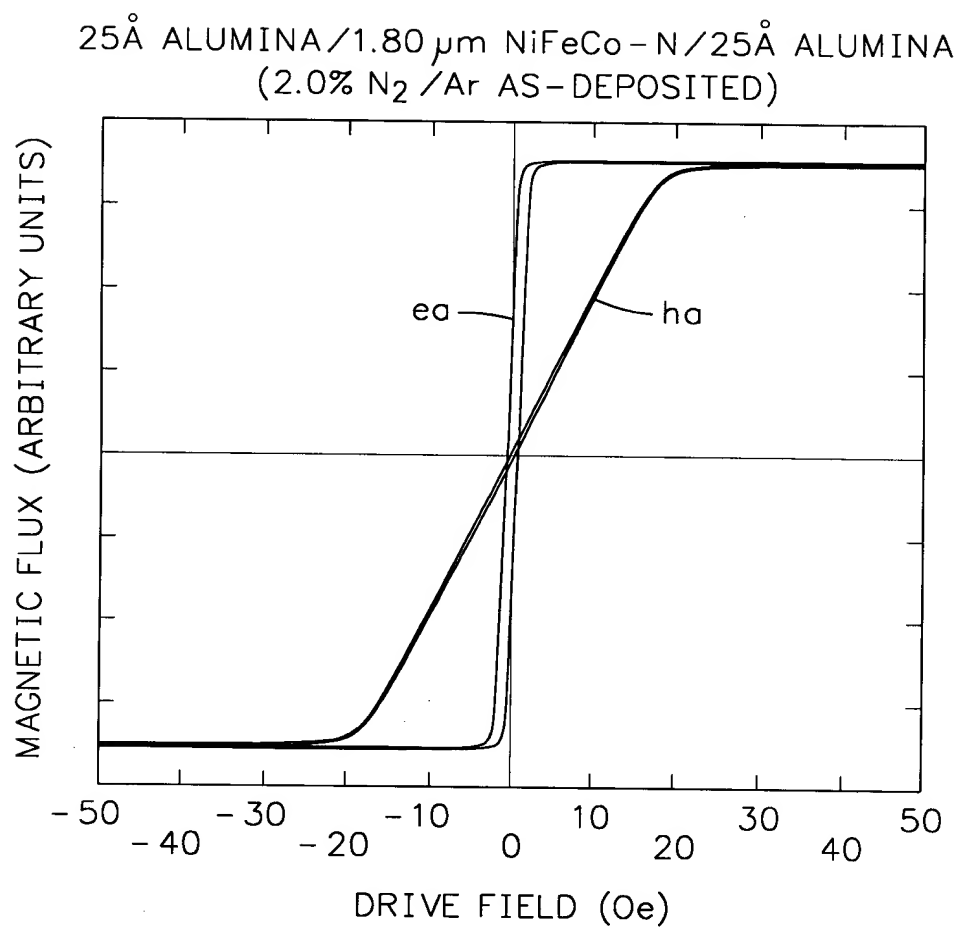


FIG. 24
(EXAMPLE XV)

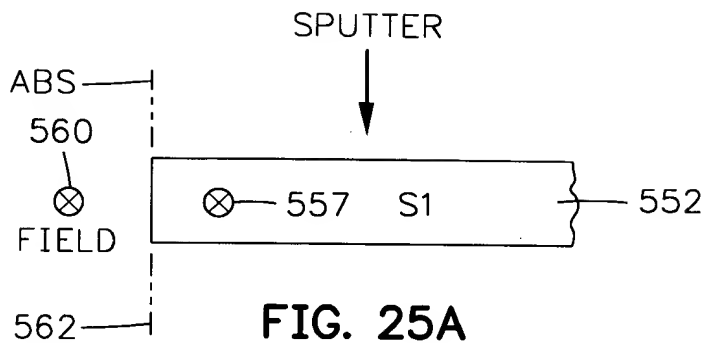


FIG. 25A

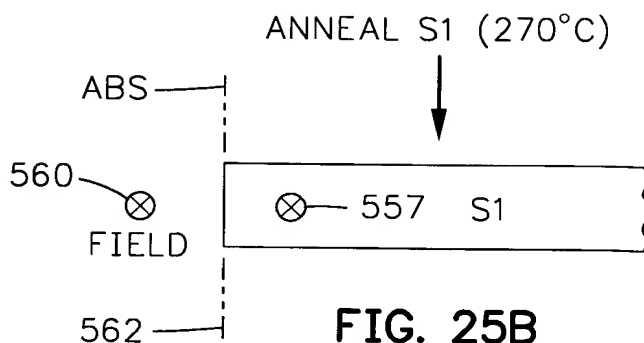


FIG. 25B

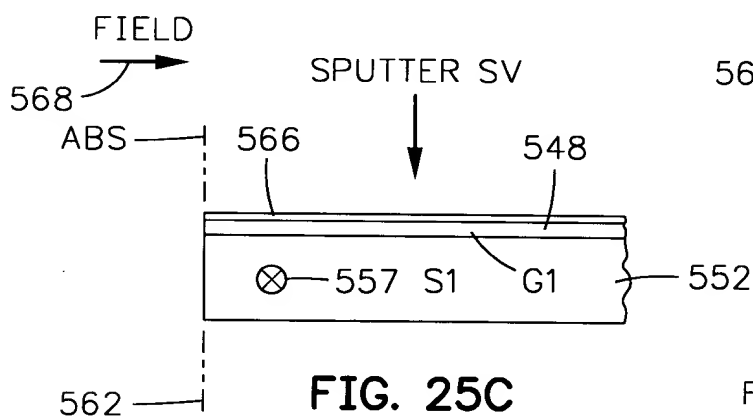


FIG. 25C

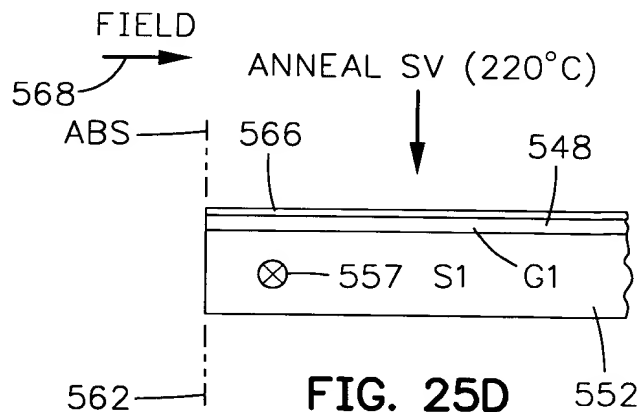


FIG. 25D

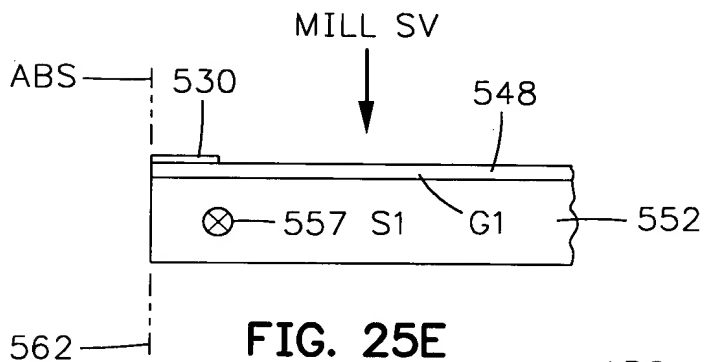


FIG. 25E

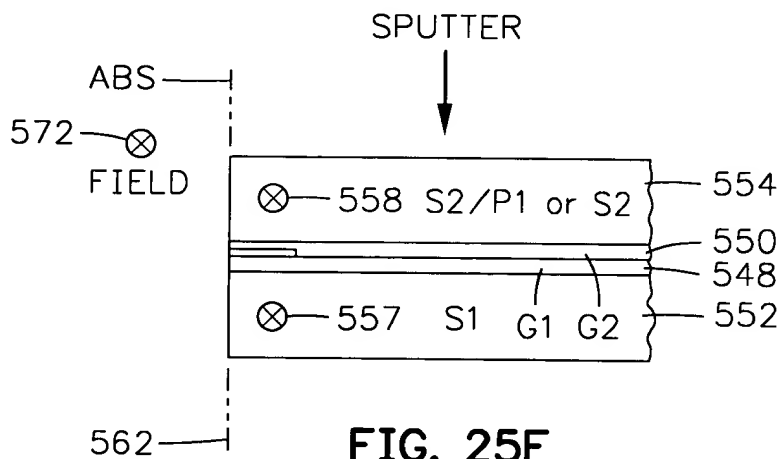
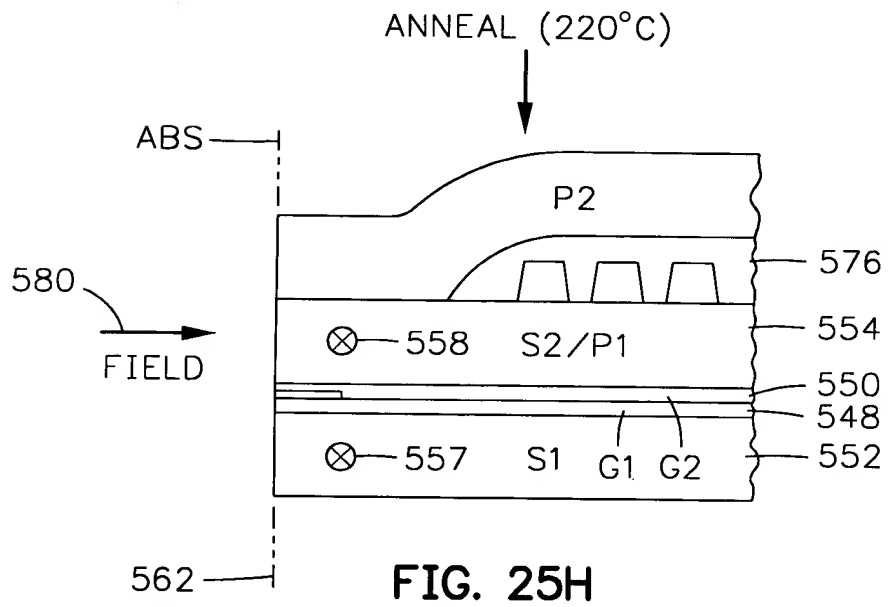
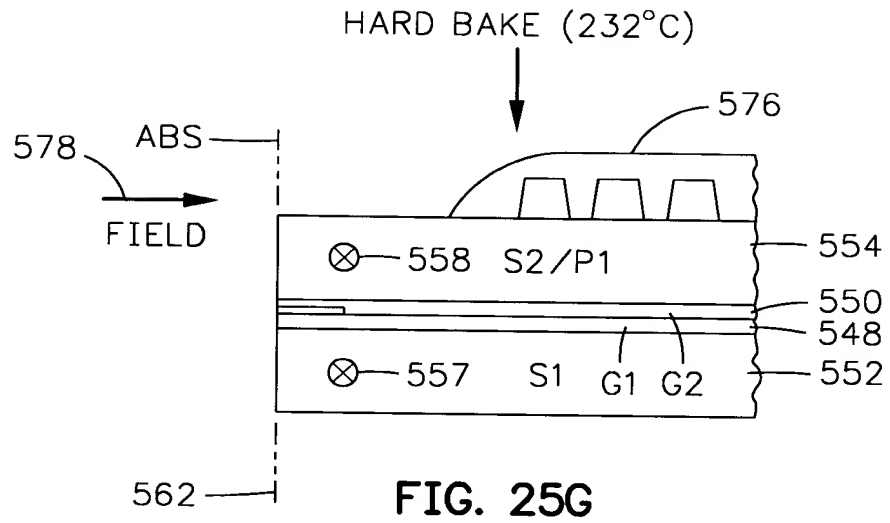


FIG. 25F



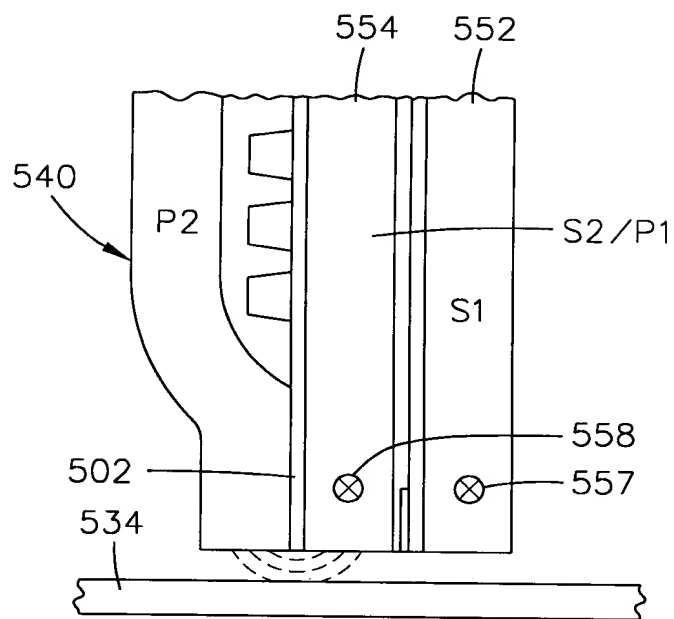


FIG. 26

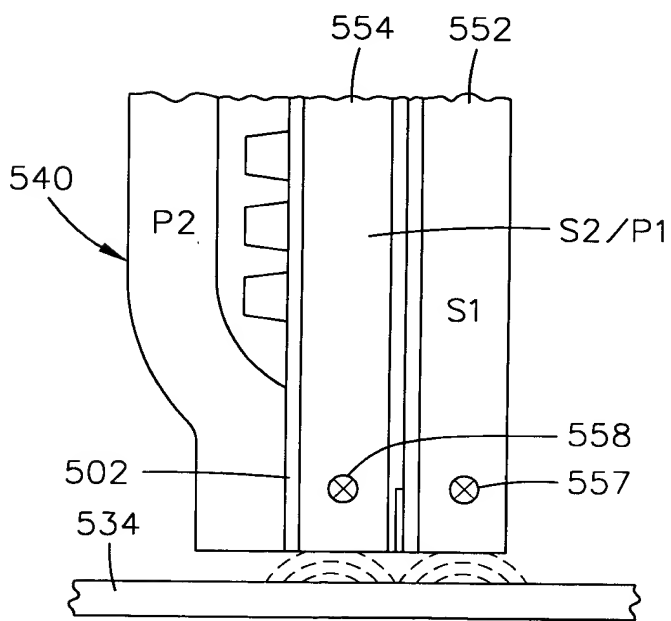


FIG. 27

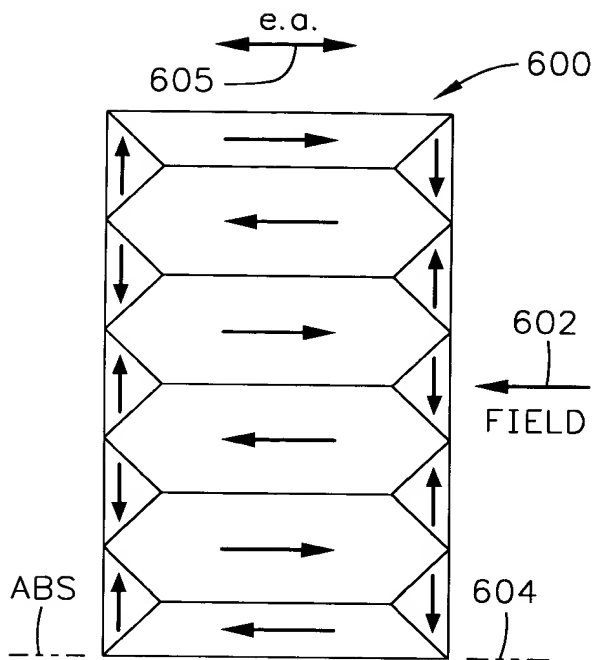


FIG. 28A
(PRIOR ART)

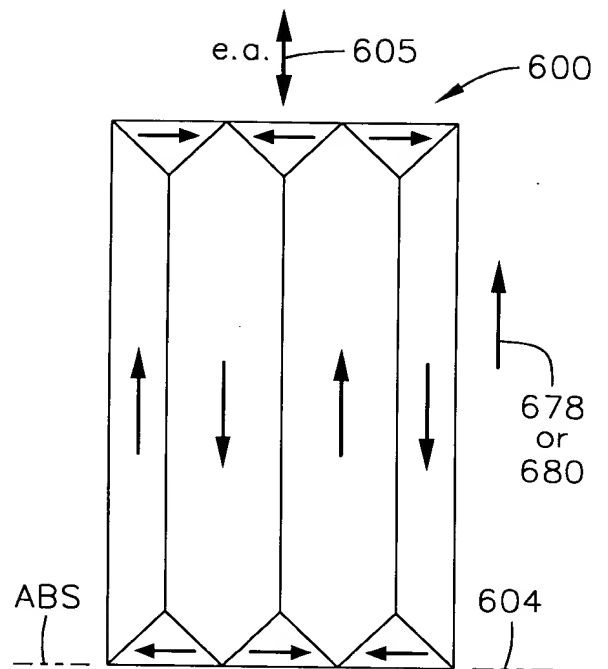
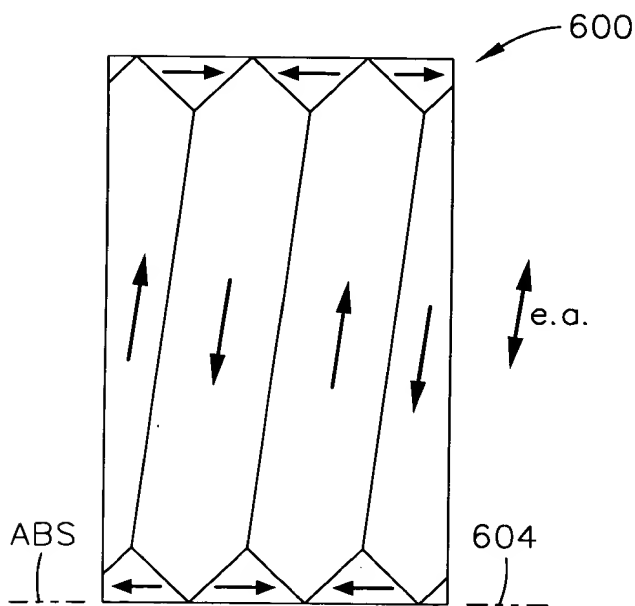


FIG. 28B
(PRIOR ART)



↑
WRITE OR DISK FIELD

FIG. 28C
(PRIOR ART)

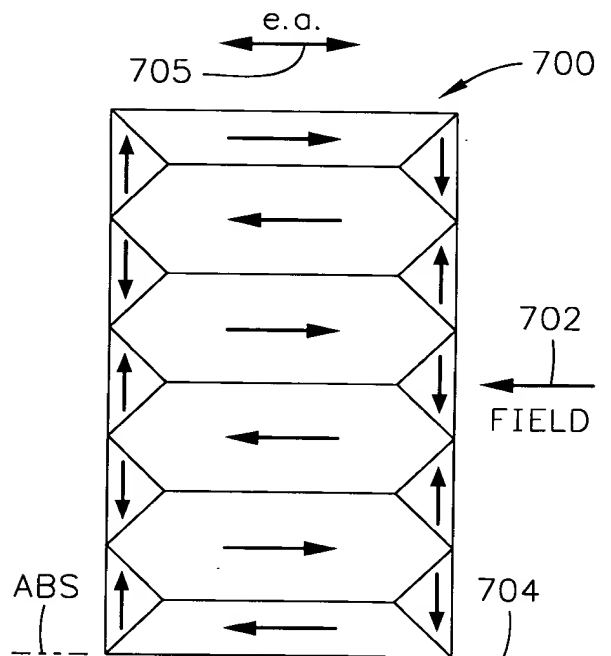


FIG. 29A

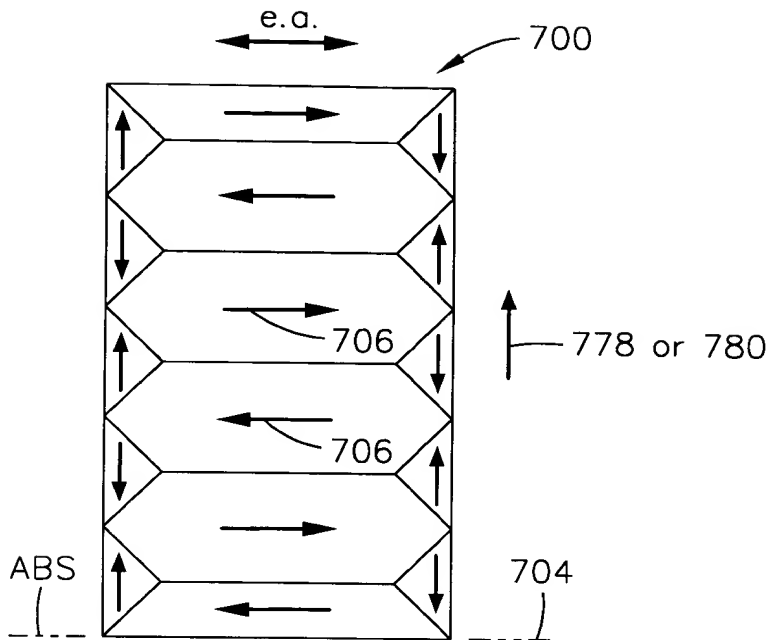


FIG. 29B
 NiFeCo [-O] - N AFTER HARDBAKE
 ANNEALING OR RESETTING
 IN THE PRESENCE OF A FIELD
 PERPENDICULAR TO THE ABS

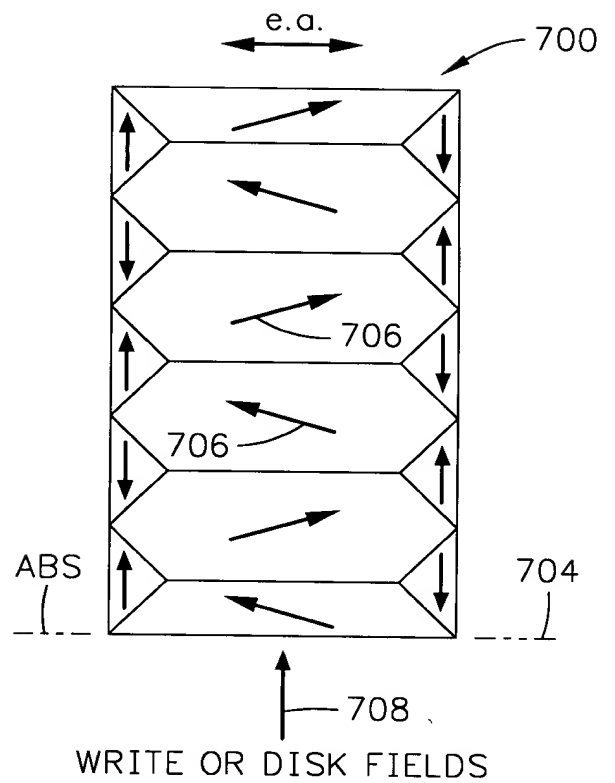


FIG. 29C

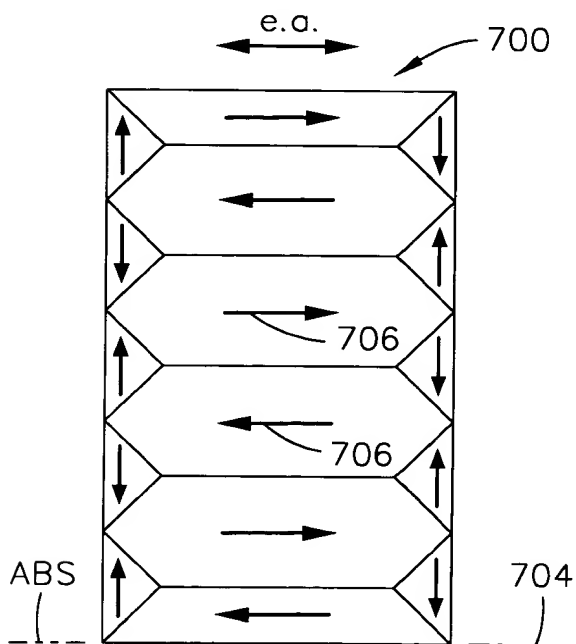


FIG. 29D